L Number	Hits	Search Text	DB	Time stamp
1	0	(5404358.pn.) and chain	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 13:58
2	1	(5404358.pn.) and serial$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 14:02
3	1	(5404358.pn.) and serial$2 and switch$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 14:14
4	5	(second adj scan adj register$1) and chain$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 14:39
5	35	scan adj register$1 adj chain$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:05
6	1	(scan adj register$1 adj chain$1) with bypass$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:20
7	93	(scan adj chain$1) with bypass$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:21
8	36	(scan adj chain$1) with register with bypass$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 16:25
9	0	(scan adj chain$1) with bypass$3 with switch$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:26
10	3	(scan with chain$1) with bypass$3 with switch$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:27
11	2	((scan with chain$1) with bypass$3 with switch$3) and (semiconductor or IC)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:28
12	4	((register with chain$1) with bypass$3 with switch$3) and (semiconductor or IC)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:29
13	2	5491666.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 17:39
14	3	6708304.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 17:39

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-	2	20020144200.pn.		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/05 15:46
-	0	(714/726.pn.) and scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and analog and (internal adj circuit) and pin$1 and (scan adj register$1) and (input adj output)		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/05 15:50
-	13	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and analog and (internal adj circuit) and pin$1 and (scan adj register$1) and (input adj output)		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/05 15:59
-	4	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and analog and (internal adj circuit) and pin$1 and (scan adj register$1) and (input adj output) and (short with wiring)		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 11:00
-	2	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and analog and (internal adj circuit) and pin$1 and (scan adj register$1) and (input adj output) and (analog with wiring)		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 11:01
-	6	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and analog and (internal adj circuit) and pin$1 and (scan adj register$1) and (input adj output) and (analog with input)		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 11:06
-	2	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and (internal adj circuit) and pin$1 and (scan adj register$1) and (input adj output) and (analog with pin$1)		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 11:07
-	32	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and pin$1 and (scan adj register$1) and (input adj output) and (analog with pin$1)		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:35
-	22	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and pin$1 and (scan adj register$1) and (input adj output) and (analog with pin$1) and (JTAG with scan$4)		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:28
-	2	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and pin$1 and ((scan adj register$1) with ((input adj output) adj pin)) and (analog with pin$1)		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 14:56
-	2	5322989.pn.		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 15:58
-	0	JP05322989.pn.		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 15:59
-	0	JP5322989.pn.		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 15:59

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–	1	05322989.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:01
–	112834	TORU.INV.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:02
–	112834	TORU.IN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:02
–	0	TORU-SHIONO.IN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:03
–	2	TORU-SH$4.IN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:03
–	0	TORU-SHIONO.IN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:06
–	2	11038091.PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:06
–	2	20020144200.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:36
–	144	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and (scan adj register$1) and (JTAG with scan$4 with register)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:29
–	41	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and (scan adj register$1) and (JTAG with scan$4 with register) and (JTAG with specification)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:30
–	9	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and (scan adj register$1) and (JTAG with scan$4 with register) and (JTAG with specification) and (register with chain) and (control$3 with (scan adj register))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:35
–	1	scan$4 and test$3 and (semiconductor$1 or (integrated adj circuit$1) or IC) and (scan adj register$1) and (JTAG adj (scan$4 adj register)) and (JTAG with specification) and (register with chain) and (control$3 with (scan adj register))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:35